



ALPHA & OMEGA
SEMICONDUCTOR

AOC2804B

20V Common-Drain Dual N-Channel AlphaMOS

General Description

- Trench Power AlphaMOS (αMOS LV) technology
- Low $R_{SS(ON)}$
- Fully protected AlphaDFN package
- With ESD protection to improve battery performance and safety
- Common drain configuration for design simplicity
- RoHS and Halogen-Free Compliant

Applications

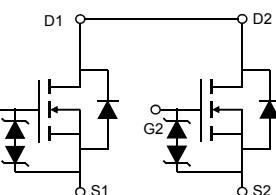
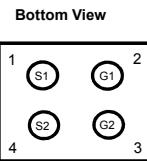
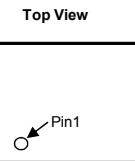
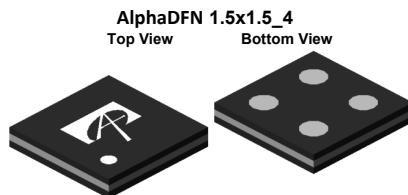
- Battery protection switch
- Mobile device battery charging and discharging

Product Summary

V_{SS}	20V
$R_{SS(ON)}$ (at $V_{GS}=4.5V$)	< 34mΩ
$R_{SS(ON)}$ (at $V_{GS}=4.0V$)	< 38mΩ
$R_{SS(ON)}$ (at $V_{GS}=3.7V$)	< 40mΩ
$R_{SS(ON)}$ (at $V_{GS}=3.1V$)	< 45mΩ
$R_{SS(ON)}$ (at $V_{GS}=2.5V$)	< 56mΩ

Typical ESD protection

HBM Class 3A



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOC2804B	AlphaDFN 1.5x1.5_4	Tape & Reel	3000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Rating	Units
Source-Source Voltage	V_{SS}	20	V
Gate-Source Voltage	V_{GS}	± 12	V
Source Current(DC) ^{Note1}	I_S $T_A=25^\circ C$	6	A
Source Current(Pulse) ^{Note2}	I_{SM}	60	
Power Dissipation ^{Note1}	P_D $T_A=25^\circ C$	1.3	W
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Units
Maximum Junction-to-Ambient $t \leq 10s$	$R_{θJA}$	85	°C/W
Maximum Junction-to-Ambient Steady-State		96	°C/W

Note 1. I_S rated value is based on bare silicon. Mounted on 70mmx70mm FR-4 board.

Note 2. PW <10 μs pulses, duty cycle 1% max.

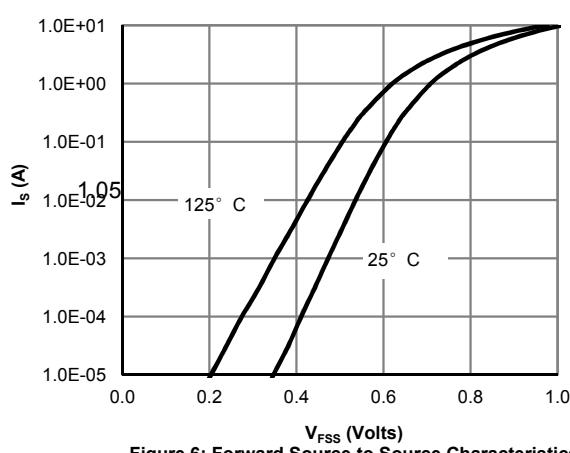
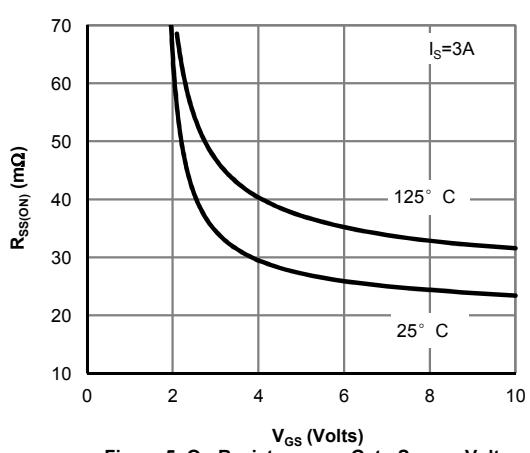
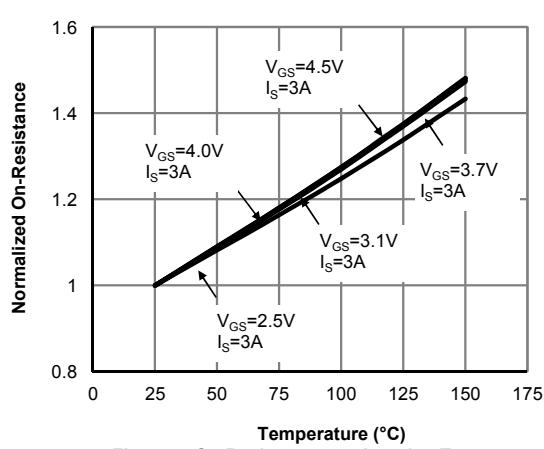
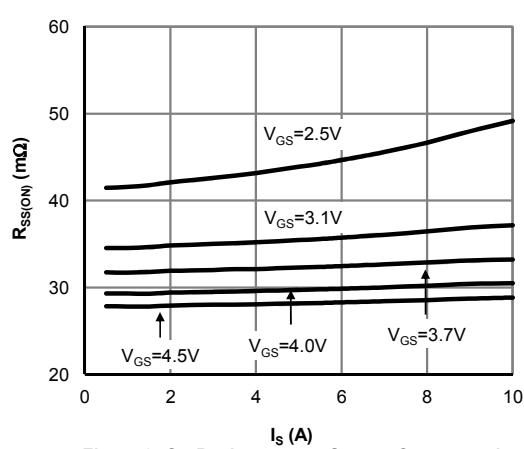
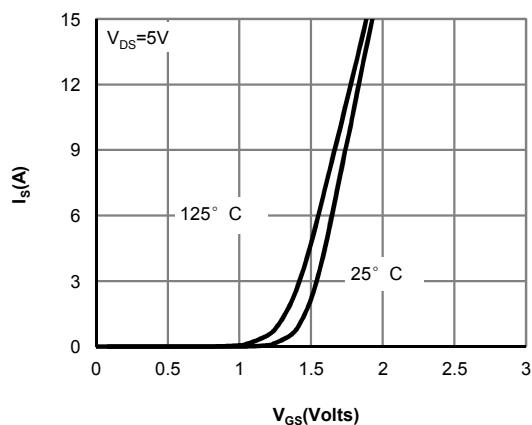
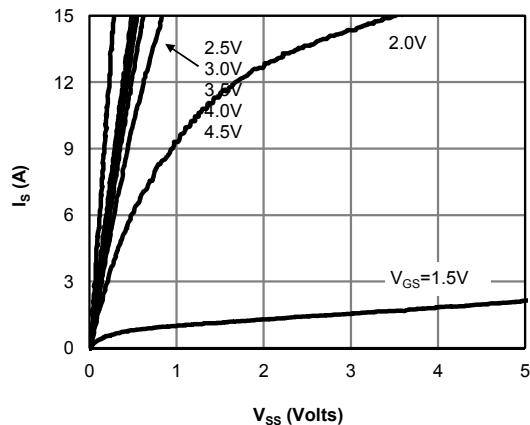
Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units	
STATIC PARAMETERS							
BV_{SSS}	Source-Source Breakdown Voltage	$I_S=250\mu\text{A}, V_{GS}=0\text{V}$	Test Circuit 6	20		V	
I_{SSS}	Zero Gate Voltage Source Current	$V_{SS}=20\text{V}, V_{GS}=0\text{V}$	Test Circuit 1		1	μA	
			$T_J=55^\circ\text{C}$		5		
I_{GSS}	Gate leakage current	$V_{SS}=0\text{V}, V_{GS}=\pm 10\text{V}$	Test Circuit 2		± 10	μA	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{SS}=V_{GS}, I_S=250\mu\text{A}$	Test Circuit 3	0.5	0.9	1.3	V
$R_{SS(\text{ON})}$	Static Source to Source On-Resistance	$V_{GS}=4.5\text{V}, I_S=3\text{A}$	Test Circuit 4	20	28	34	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		27	38.5	47	
		$V_{GS}=4.0\text{V}, I_S=3\text{A}$	Test Circuit 4	22	30.5	38	$\text{m}\Omega$
		$V_{GS}=3.7\text{V}, I_S=3\text{A}$	Test Circuit 4	23	32	40	$\text{m}\Omega$
		$V_{GS}=3.1\text{V}, I_S=3\text{A}$	Test Circuit 4	25	35	45	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{SS}=5\text{V}, I_S=3\text{A}$	Test Circuit 3		20		S
V_{FSS}	Forward Source to Source Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$	Test Circuit 5		0.72	1	V
DYNAMIC PARAMETERS							
R_g	Gate resistance	$f=1\text{MHz}$			2	$\text{k}\Omega$	
SWITCHING PARAMETERS							
Q_g	Total Gate Charge	$V_{G1S1}=4.5\text{V}, V_{SS}=10\text{V}, I_S=3\text{A}$			9.5	nC	
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{G1S1}=4.5\text{V}, V_{SS}=10\text{V}, R_L=3.3\Omega,$ $R_{\text{GEN}}=3\Omega$	Test Circuit 8		0.85	μs	
t_r	Turn-On Rise Time				2.2	μs	
$t_{D(\text{off})}$	Turn-Off DelayTime				2.0	μs	
t_f	Turn-Off Fall Time				4.3	μs	

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





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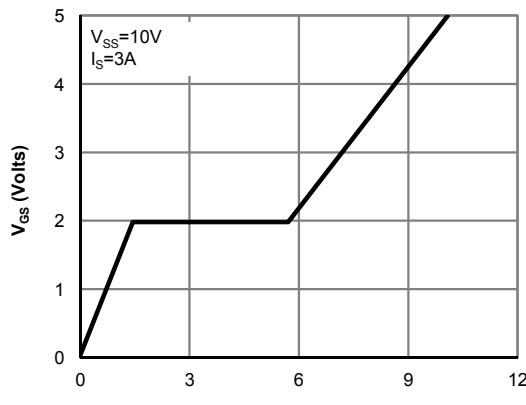


Figure 7: Gate-Charge Characteristics

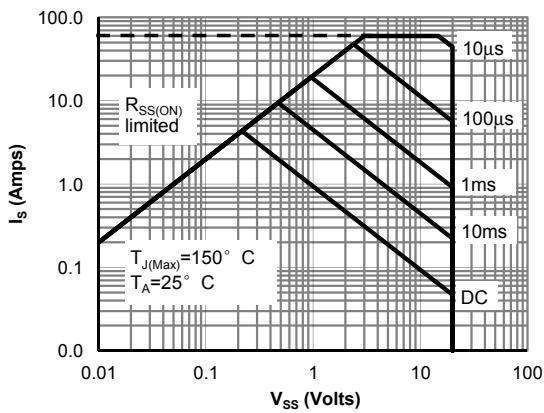


Figure 9: Maximum Forward Biased Safe Operating Area (Note1)

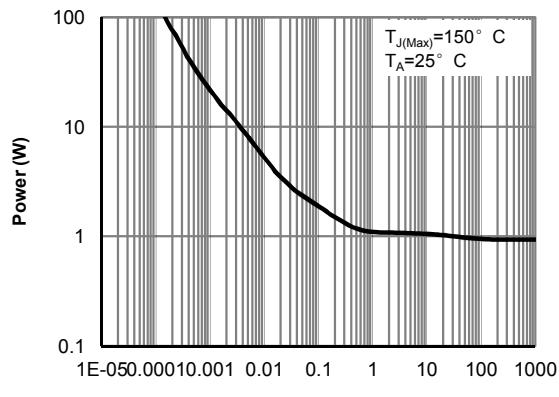


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note1)

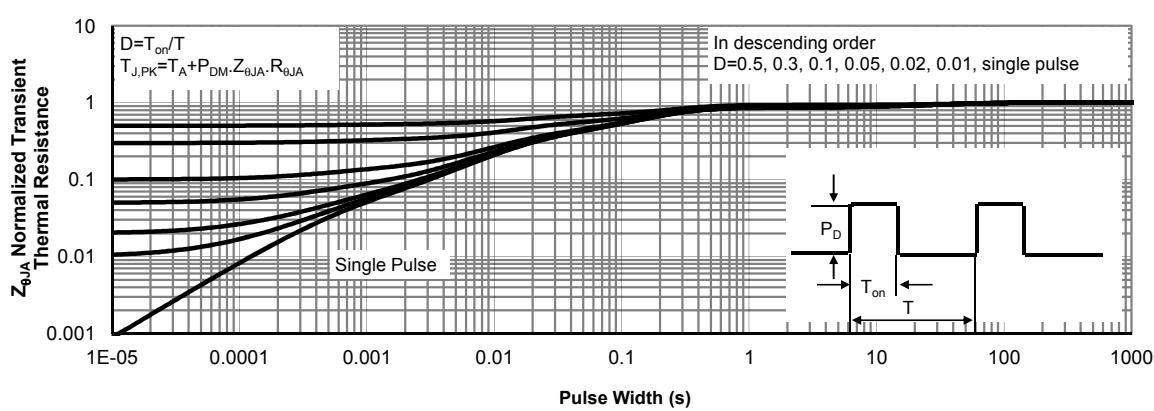
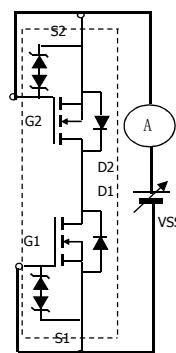


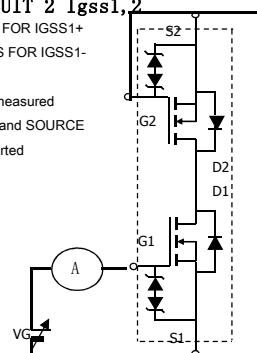
Figure 11: Normalized Maximum Transient Thermal Impedance (Note1)



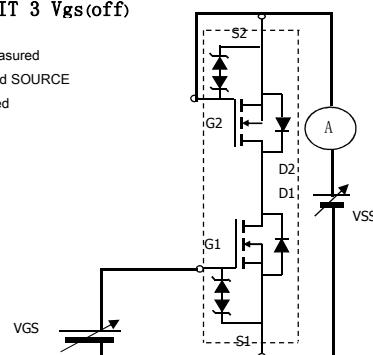
TEST CIRCUIT 1 Isss
POSITIVE VSS FOR ISSS+
NEGATIVE VSS FOR ISSS-



TEST CIRCUIT 2 Igss1,2
POSITIVE VGS FOR IGSS1+
NEGATIVE VGS FOR IGSS1-

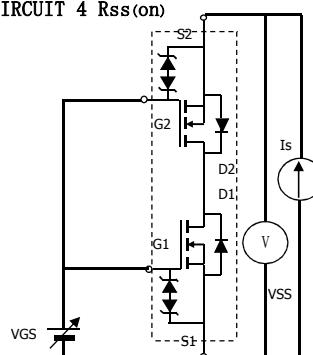


TEST CIRCUIT 3 Vgs(off)
When FET1 is measured
between GATE and SOURCE
of FET2 are shorted

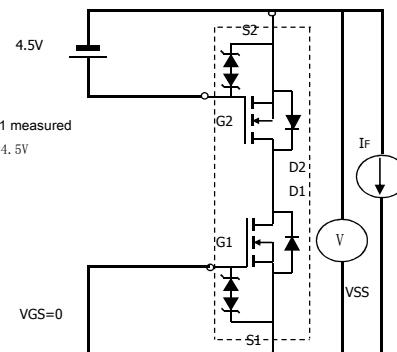


TEST CIRCUIT 4 Rss(on)

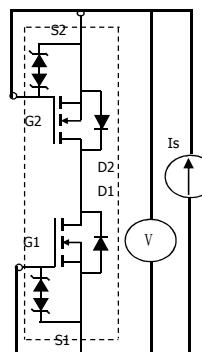
Vss/Is



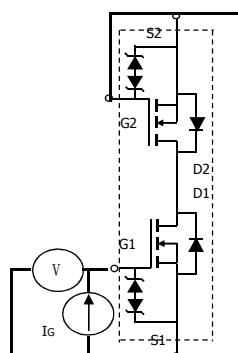
TEST CIRCUIT 5 VF(ss)1,2
When FET1 measured
FET2 VGS=4.5V
VGS=0



TEST CIRCUIT 6 BVdss
POSITIVE VSS FOR ISSS+
NEGATIVE VSS FOR ISSS-



TEST CIRCUIT 7 BVgs01,2
POSITIVE VSS FOR ISSS+
NEGATIVE VSS FOR ISSS-
When FET1 is measured
between GATE and SOURCE
of FET2 are shorted



TEST CIRCUIT 8
Switching time

